

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/618,687	OGAWA ET AL.	
			Examiner	Art Unit	Page 1 of 1
			Karl E. Group	1755	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,708,652	11-1987	Fujiu et al.	433/201.1
	B	US-5,120,340	06-1992	Ducheyne et al.	65/17.5
	C	US-5,658,332	08-1997	Ducheyne et al.	128/898
	D	US-5,634,956	06-1997	Suh et al.	65/33.1
	E	US-5,981,412	11-1999	Hench et al.	501/5
	F	US-6,228,386	05-2001	Yang, Shih-Liang S.	424/426
	G	US-6,482,427	11-2002	Yang, Shih-Liang S.	424/426
	H	US-2004/0235637	11-2004	Berger et al.	501/072
	I	US-2005/0009682	01-2005	Zimmer et al.	501/005
	J	US-4,437,192	03-1984	Fujiu et al.	623/23.56
	K	US-4,135,935	01-1979	Pfeil et al.	106/35
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	61-205637	09-1986	Japan	Nippon	-/-
	O	0577342	01-1994	EP	Bonfield et al	-/-
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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